

-	0	(backside or back adj side or back-side) near8 electrode and dram.ti,ab,clm. and (test or testing or probe or probing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:40
-	0	trench and (dram or memory adj device).ti,ab,clm. and (testing or probing) and (back-side or backside or back adj side) near12 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:43
-	4	trench and (dram or memory adj device) and (testing or probing) and (back-side or backside or back adj side) near12 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:45
-	3	257/48.ccls. and (back-side or back adj side or backside) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:45
-	1608	257/48	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 19:09
-	907	(257/48).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 19:44
-	3	((257/48).CCLS.) and (back adj side or backside or back-side) near3 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 19:52
-	1	(257/48 or ((257/68).CCLS.) or ((257/71).CCLS.) or ((257/301).CCLS.) or ((257/302).CCLS.) or ((257/303).CCLS.) or ((257/304).CCLS.) or ((257/305).CCLS.) or ((257/905) or (257/906)).CCLS.) or ((324/158).CCLS.) or ((324/537).CCLS.) or ((324/765).CCLS.) or ((324/766).CCLS.) or ((324/767).CCLS.) or ((324/768).CCLS.) or ((324/769).CCLS.) or ((714/5).CCLS.) or ((714/42).CCLS.) or ((714/718).CCLS.) or ((714/719).CCLS.) or ((714/720).CCLS.) or ((714/721).CCLS.) or ((714/722).CCLS.) or ((714/723).CCLS.) or ((714/763).CCLS.) or ((714/773).CCLS.) or ((438/18).CCLS.)) and (back-side or backside or back adj side) near5 electrode and memory.ti,ab,clm. and (testing or probing or test or probe)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:05
-	2	(257/48 or ((257/68).CCLS.) or ((257/71).CCLS.) or ((257/301).CCLS.) or ((257/302).CCLS.) or ((257/303).CCLS.) or ((257/304).CCLS.) or ((257/305).CCLS.) or ((257/905) or (257/906)).CCLS.) or ((324/158).CCLS.) or ((324/537).CCLS.) or ((324/765).CCLS.) or ((324/766).CCLS.) or ((324/767).CCLS.) or ((324/768).CCLS.) or ((324/769).CCLS.) or ((714/5).CCLS.) or ((714/42).CCLS.) or ((714/718).CCLS.) or ((714/719).CCLS.) or ((714/720).CCLS.) or ((714/721).CCLS.) or ((714/722).CCLS.) or ((714/723).CCLS.) or ((714/763).CCLS.) or ((714/773).CCLS.) or ((438/18).CCLS.)) and (back-side or backside or back adj side) adj electrode near12 (testing or probing or diagnostic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:11

-	0	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) adj electrode near12 (testing or probing or diagnostic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:12
-	5	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) adj electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:16
-	6	(trench near8 (memory adj device or dram)) and (back-side or backside or back adj side) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:26
-	11	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:36
-	7	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) near2 (ground or grounded or grounding)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:42
-	0	contact-mode near12 back-side near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:43
-	0	(contact adj mode or contact-mode) near12 back-side near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:46
-	0	(contact adj mode or contact-mode) near12 (bottom or back-side or backside or back adj side) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 20:46
-	1	vallett.in.	US-PGPUB	2003/02/15 21:25
-	0	product adj line adj macro adj design	US-PGPUB	2003/02/15 21:25
-	0	product adj line adj macro adj design	US-PGPUB	2003/02/15 21:25
-	0	product adj line adj macro adj design	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 21:26
-	48	product adj line near3 design	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 21:26
-	2	("6078057").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 21:38
-	2	("5990562").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 21:38
-	2	("6277659").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/02/15 21:38

-	25	(US-6380555-\$ or US-6300647-\$ or US-6301121-\$ or US-6377067-\$ or US-6339228-\$ or US-6310361-\$ or US-5523586-\$ or US-6072323-\$ or US-5665978-\$ or US-6498396-\$ or US-6452208-\$ or US-5408131-\$ or US-6309897-\$ or US-4905065-\$ or US-4791463-\$ or US-4914739-\$ or US-5309446-\$ or US-6392307-\$ or US-6153891-\$ or US-6277659-\$ or US-5990562-\$ or US-6078057-\$).did. or (US-20020118035-\$ or US-20010006233-\$ or US-20020063250-\$).did.	USPAT; US-PGPUB	2003/08/04 11:01
-	653	(257/48).CCLS.	USPAT; US-PGPUB	2003/08/04 11:35
-	61	((257/48).CCLS.) and trench	USPAT; US-PGPUB	2003/08/04 13:14
-	2481	((257/68) or (257/71) or (257/49) or (257/66) or (257/905) or (257/906) or (257/301) or (257/302) or (257/303) or (257/304) or (257/305)).CCLS.	USPAT; US-PGPUB	2003/08/04 16:16
-	29	((257/68) or (257/71) or (257/49) or (257/66) or (257/905) or (257/906) or (257/301) or (257/302) or (257/303) or (257/304) or (257/305)).CCLS.) and (trench groove) and (back-side back adj side) ("6599778").PN.	USPAT; US-PGPUB	2003/08/04 13:20
-	1	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.	USPAT USPAT; US-PGPUB	2003/08/04 13:21 2003/08/04 16:17
-	3374	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and trench	USPAT; US-PGPUB	2003/08/04 16:58
-	41	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and (trench groove)	USPAT; US-PGPUB	2003/08/04 16:58
-	178	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and (trench groove)	USPAT; US-PGPUB	2003/08/04 16:58
-	137	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and (trench groove) not (((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and trench)	USPAT; US-PGPUB	2003/08/04 16:58
-	33	(US-6309897-\$ or US-4905065-\$ or US-6277659-\$ or US-6153891-\$ or US-6392307-\$ or US-5408131-\$ or US-5523586-\$ or US-6377067-\$ or US-6301121-\$ or US-6300647-\$ or US-6380555-\$ or US-6452208-\$ or US-6498396-\$ or US-5665978-\$ or US-6072323-\$ or US-4791463-\$ or US-4914739-\$ or US-5309446-\$ or US-5990562-\$ or US-6545490-\$ or US-6599778-\$ or US-5734176-\$ or US-6452209-\$ or US-6576922-\$ or US-6576923-\$ or US-6310361-\$).did. or (US-6339228-\$ or US-6078057-\$).did. or (US-20020063250-\$ or US-20010006233-\$ or US-20020118035-\$ or US-20030111733-\$ or US-20030136993-\$).did.	USPAT; US-PGPUB	2003/08/04 18:22

-	25	((US-6309897-\$ or US-4905065-\$ or US-6277659-\$ or US-6153891-\$ or US-6392307-\$ or US-5408131-\$ or US-5523586-\$ or US-6377067-\$ or US-6301121-\$ or US-6300647-\$ or US-6380555-\$ or US-6452208-\$ or US-6498396-\$ or US-5665978-\$ or US-6072323-\$ or US-4791463-\$ or US-4914739-\$ or US-5309446-\$ or US-5990562-\$ or US-6545490-\$ or US-6599778-\$ or US-5734176-\$ or US-6452209-\$ or US-6576922-\$ or US-6576923-\$ or US-6310361-\$).did. or (US-6339228-\$ or US-6078057-\$).did. or (US-20020063250-\$ or US-20010006233-\$ or US-20020118035-\$ or US-20030111733-\$ or US-20030136993-\$).did.) and (memory dram) ("6599778").PN. ("6545490").PN.	USPAT; US-PGPUB	2003/08/04 18:23
-	1		USPAT	2003/08/04 18:56
-	1		USPAT	2003/08/04 18:56
-	33	(US-6300647-\$ or US-5734176-\$ or US-6452208-\$ or US-6380555-\$ or US-6452209-\$ or US-6339228-\$ or US-6310361-\$ or US-4905065-\$ or US-6153891-\$ or US-6309897-\$ or US-6277659-\$ or US-6392307-\$ or US-5523586-\$ or US-6498396-\$ or US-6301121-\$ or US-6545490-\$ or US-6377067-\$ or US-6599778-\$ or US-5408131-\$ or US-6078057-\$ or US-5990562-\$ or US-5309446-\$ or US-4914739-\$ or US-4791463-\$ or US-5665978-\$ or US-6576922-\$).did. or (US-6072323-\$ or US-6576923-\$).did. or (US-20010006233-\$ or US-20020063250-\$ or US-20020118035-\$ or US-20030136993-\$ or US-20030111733-\$).did.	USPAT; US-PGPUB	2003/12/19 18:31

L Number	Hits	Search Text	DB	Time stamp
1	677	(257/301).CCLS.	USPAT; US-PGPUB	2003/12/23 11:24
2	1859	(257/296).CCLS.	USPAT; US-PGPUB	2003/12/23 11:40
3	29	((257/296).CCLS.) and (contact electrode) near4 (back rear back-side) and (trench groove) and (memory dram).ti,ab,clm.	USPAT; US-PGPUB	2003/12/23 11:42
4	1181	((438/243) or (438/700)).CCLS.	USPAT; US-PGPUB	2003/12/23 11:42
5	19	((438/243) or (438/700)).CCLS.) and (contact electrode) near4 (back rear back-side) and (trench groove) and (memory dram).ti,ab,clm.	USPAT; US-PGPUB	2003/12/23 11:43
6	697	(257/48).CCLS.	USPAT; US-PGPUB	2003/12/23 11:43
7	0	((257/48).CCLS.) and (contact electrode) near4 (back rear back-side) and (trench groove) and (memory dram).ti,ab,clm.	USPAT; US-PGPUB	2003/12/23 11:43
-	0	("method near3 testing near3 (semiconductor adj device or dram).ti,ab,clm.").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/20 15:53
-	87	method near3 testing near3 (semiconductor adj device or dram).ti.	USPAT	2003/02/15 14:26
-	70	method near2 testing near2 (semiconductor adj device or dram).ti.	USPAT	2003/02/15 14:54
-	199	(257/68).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:56
-	118	(257/71).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:56
-	822	(257/301).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:56
-	421	(257/302).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:56
-	503	(257/303).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:56
-	396	(257/304).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:56
-	318	(257/305).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:57
-	202	((257/905) or (257/906)).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:57

-	0	(324/158).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:57
-	1321	(324/537).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:57
-	3141	(324/765).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	360	(324/766).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	575	(324/767).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	121	(324/768).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	331	(324/769).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	406	(714/5).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	365	(714/42).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	2408	(714/718).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	636	(714/719).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	153	(714/720).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:58
-	222	(714/721).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:59
-	101	(714/722).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:59

-	247	(714/723).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:59
-	810	(714/763).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:59
-	105	(714/773).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:59
-	334	(438/18).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 14:59
-	14166	257/48 or ((257/68).CCLS.) or ((257/71).CCLS.) or ((257/301).CCLS.) or ((257/302).CCLS.) or ((257/303).CCLS.) or ((257/304).CCLS.) or ((257/305).CCLS.) or ((257/905) or (257/906)).CCLS.) or ((324/158).CCLS.) or ((324/537).CCLS.) or ((324/765).CCLS.) or ((324/766).CCLS.) or ((324/767).CCLS.) or ((324/768).CCLS.) or ((324/769).CCLS.) or ((714/5).CCLS.) or ((714/42).CCLS.) or ((714/718).CCLS.) or ((714/719).CCLS.) or ((714/720).CCLS.) or ((714/721).CCLS.) or ((714/722).CCLS.) or ((714/723).CCLS.) or ((714/763).CCLS.) or ((714/773).CCLS.) or ((438/18).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 15:01
-	50	257/48 or ((257/68).CCLS.) or ((257/71).CCLS.) or ((257/301).CCLS.) or ((257/302).CCLS.) or ((257/303).CCLS.) or ((257/304).CCLS.) or ((257/305).CCLS.) or ((257/905) or (257/906)).CCLS.) or ((324/158).CCLS.) or ((324/537).CCLS.) or ((324/765).CCLS.) or ((324/766).CCLS.) or ((324/767).CCLS.) or ((324/768).CCLS.) or ((324/769).CCLS.) or ((714/5).CCLS.) or ((714/42).CCLS.) or ((714/718).CCLS.) or ((714/719).CCLS.) or ((714/720).CCLS.) or ((714/721).CCLS.) or ((714/722).CCLS.) or ((714/723).CCLS.) or ((714/763).CCLS.) or ((714/773).CCLS.) or ((438/18).CCLS.) and trench and dram and (test or testing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 15:03
-	14	257/48 or ((257/68).CCLS.) or ((257/71).CCLS.) or ((257/301).CCLS.) or ((257/302).CCLS.) or ((257/303).CCLS.) or ((257/304).CCLS.) or ((257/305).CCLS.) or ((257/905) or (257/906)).CCLS.) or ((324/158).CCLS.) or ((324/537).CCLS.) or ((324/765).CCLS.) or ((324/766).CCLS.) or ((324/767).CCLS.) or ((324/768).CCLS.) or ((324/769).CCLS.) or ((714/5).CCLS.) or ((714/42).CCLS.) or ((714/718).CCLS.) or ((714/719).CCLS.) or ((714/720).CCLS.) or ((714/721).CCLS.) or ((714/722).CCLS.) or ((714/723).CCLS.) or ((714/763).CCLS.) or ((714/773).CCLS.) or ((438/18).CCLS.) and trench and dram.ti.ab. and (test or testing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 15:25
-	7	(US-6310361-\$ or US-6339228-\$ or US-6377067-\$ or US-4791463-\$ or US-4905065-\$ or US-4914739-\$ or US-5309446-\$).did.	USPAT	2003/02/15 15:10

-	7	((US-6310361-\$ or US-6339228-\$ or US-6377067-\$ or US-4791463-\$ or US-4905065-\$ or US-4914739-\$ or US-5309446-\$).did.) and trench and dram.ti,ab. and (test or testing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 15:39
-	0	(257/48 and trench near12 contact).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 15:40
-	26	257/48 and trench near12 contact	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 16:22
-	88	(back-side or back adj side) near5 (testing or probing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 16:24
-	2	(back-side or back adj side) near5 (testing or probing) and 257/48.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 16:27
-	3	(back-side or back adj side) near5 thinning and 257/48.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 16:27
-	10	(US-5309446-\$ or US-4914739-\$ or US-4905065-\$ or US-4791463-\$ or US-6078057-\$ or US-5990562-\$ or US-6377067-\$ or US-6310361-\$ or US-6339228-\$).did. or (US-20020118035-\$).did.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:12
-	5	((US-5309446-\$ or US-4914739-\$ or US-4905065-\$ or US-4791463-\$ or US-6078057-\$ or US-5990562-\$ or US-6377067-\$ or US-6310361-\$ or US-6339228-\$).did. or (US-20020118035-\$).did.) and layer near12 substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:18
-	0	back-side near5 substrate near5 dram near5 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:19
-	0	back-side near5 substrate near5 electrode and dram.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:19
-	0	back-side near8 substrate near8 electrode and dram.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:19
-	0	back-side near8 electrode and dram.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:20
-	9	(backside or back adj side or back-side) near8 electrode and dram.ti,ab,clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:41

-	0	(backside or back adj side or back-side) near8 electrode and dram.ti,ab,clm. and (test or testing or probe or probing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:40
-	0	trench and (dram or memory adj device).ti,ab,clm. and (testing or probing) and (back-side or backside or back adj side) near12 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:43
-	4	trench and (dram or memory adj device) and (testing or probing) and (back-side or backside or back adj side) near12 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:45
-	3	257/48.ccls. and (back-side or back adj side or backside) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 18:45
-	1608	257/48	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 19:09
-	907	(257/48).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 19:44
-	3	((257/48).CCLS.) and (back adj side or backside or back-side) near3 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 19:52
-	1	(257/48 or ((257/68).CCLS.) or ((257/71).CCLS.) or ((257/301).CCLS.) or ((257/302).CCLS.) or ((257/303).CCLS.) or ((257/304).CCLS.) or ((257/305).CCLS.) or ((257/905) or (257/906)).CCLS.) or ((324/158).CCLS.) or ((324/537).CCLS.) or ((324/765).CCLS.) or ((324/766).CCLS.) or ((324/767).CCLS.) or ((324/768).CCLS.) or ((324/769).CCLS.) or ((714/5).CCLS.) or ((714/42).CCLS.) or ((714/718).CCLS.) or ((714/719).CCLS.) or ((714/720).CCLS.) or ((714/721).CCLS.) or ((714/722).CCLS.) or ((714/723).CCLS.) or ((714/763).CCLS.) or ((714/773).CCLS.) or ((438/18).CCLS.)) and (back-side or backside or back adj side) near5 electrode and memory.ti,ab,clm. and (testing or probing or test or probe)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:05
-	2	(257/48 or ((257/68).CCLS.) or ((257/71).CCLS.) or ((257/301).CCLS.) or ((257/302).CCLS.) or ((257/303).CCLS.) or ((257/304).CCLS.) or ((257/305).CCLS.) or ((257/905) or (257/906)).CCLS.) or ((324/158).CCLS.) or ((324/537).CCLS.) or ((324/765).CCLS.) or ((324/766).CCLS.) or ((324/767).CCLS.) or ((324/768).CCLS.) or ((324/769).CCLS.) or ((714/5).CCLS.) or ((714/42).CCLS.) or ((714/718).CCLS.) or ((714/719).CCLS.) or ((714/720).CCLS.) or ((714/721).CCLS.) or ((714/722).CCLS.) or ((714/723).CCLS.) or ((714/763).CCLS.) or ((714/773).CCLS.) or ((438/18).CCLS.)) and (back-side or backside or back adj side) adj electrode near12 (testing or probing or diagnostic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:11

-	0	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) adj electrode near12 (testing or probing or diagnostic)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:12
-	5	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) adj electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:16
-	6	(trench near8 (memory adj device or dram)) and (back-side or backside or back adj side) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:26
-	11	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:36
-	7	(memory adj device or dram).ti,ab,clm. and (back-side or backside or back adj side) near2 (ground or grounded or grounding)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:42
-	0	contact-mode near12 back-side near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:43
-	0	(contact adj mode or contact-mode) near12 back-side near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:46
-	0	(contact adj mode or contact-mode) near12 (bottom or back-side or backside or back adj side) near2 electrode	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 20:46
-	1	vallett.in.	US-PGPUB	2003/02/15 21:25
-	0	product adj line adj macro adj design	US-PGPUB	2003/02/15 21:25
-	0	product adj line adj macro adj design	US-PGPUB	2003/02/15 21:25
-	0	product adj line adj macro adj design	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 21:26
-	48	product adj line near3 design	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 21:26
-	2	("6078057").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 21:38
-	2	("5990562").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 21:38
-	2	("6277659").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/15 21:38

-	25	(US-6380555-\$ or US-6300647-\$ or US-6301121-\$ or US-6377067-\$ or US-6339228-\$ or US-6310361-\$ or US-5523586-\$ or US-6072323-\$ or US-5665978-\$ or US-6498396-\$ or US-6452208-\$ or US-5408131-\$ or US-6309897-\$ or US-4905065-\$ or US-4791463-\$ or US-4914739-\$ or US-5309446-\$ or US-6392307-\$ or US-6153891-\$ or US-6277659-\$ or US-5990562-\$ or US-6078057-\$).did. or (US-20020118035-\$ or US-20010006233-\$ or US-20020063250-\$).did.	USPAT; US-PGPUB	2003/08/04 11:01
-	653	(257/48).CCLS.	USPAT; US-PGPUB	2003/08/04 11:35
-	61	((257/48).CCLS.) and trench	USPAT; US-PGPUB	2003/08/04 13:14
-	2481	((257/68) or (257/71) or (257/49) or (257/66) or (257/905) or (257/906) or (257/301) or (257/302) or (257/303) or (257/304) or (257/305)).CCLS.	USPAT; US-PGPUB	2003/08/04 16:16
-	29	((257/68) or (257/71) or (257/49) or (257/66) or (257/905) or (257/906) or (257/301) or (257/302) or (257/303) or (257/304) or (257/305)).CCLS.) and (trench groove) and (back-side back adj side) ("6599778").PN.	USPAT; US-PGPUB	2003/08/04 13:20
-	1		USPAT	2003/08/04 13:21
-	3374	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.	USPAT; US-PGPUB	2003/08/04 16:17
-	41	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and trench	USPAT; US-PGPUB	2003/08/04 16:58
-	178	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and (trench groove)	USPAT; US-PGPUB	2003/08/04 16:58
-	137	((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and (trench groove) not (((324/158) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769)).CCLS.) and trench)	USPAT; US-PGPUB	2003/08/04 16:58
-	33	(US-6309897-\$ or US-4905065-\$ or US-6277659-\$ or US-6153891-\$ or US-6392307-\$ or US-5408131-\$ or US-5523586-\$ or US-6377067-\$ or US-6301121-\$ or US-6300647-\$ or US-6380555-\$ or US-6452208-\$ or US-6498396-\$ or US-5665978-\$ or US-6072323-\$ or US-4791463-\$ or US-4914739-\$ or US-5309446-\$ or US-5990562-\$ or US-6545490-\$ or US-6599778-\$ or US-5734176-\$ or US-6452209-\$ or US-6576922-\$ or US-6576923-\$ or US-6310361-\$).did. or (US-6339228-\$ or US-6078057-\$).did. or (US-20020063250-\$ or US-20010006233-\$ or US-20020118035-\$ or US-20030111733-\$ or US-20030136993-\$).did.	USPAT; US-PGPUB	2003/08/04 18:22

-	25	((US-6309897-\$ or US-4905065-\$ or US-6277659-\$ or US-6153891-\$ or US-6392307-\$ or US-5408131-\$ or US-5523586-\$ or US-6377067-\$ or US-6301121-\$ or US-6300647-\$ or US-6380555-\$ or US-6452208-\$ or US-6498396-\$ or US-5665978-\$ or US-6072323-\$ or US-4791463-\$ or US-4914739-\$ or US-5309446-\$ or US-5990562-\$ or US-6545490-\$ or US-6599778-\$ or US-5734176-\$ or US-6452209-\$ or US-6576922-\$ or US-6576923-\$ or US-6310361-\$).did. or (US-6339228-\$ or US-6078057-\$).did. or (US-20020063250-\$ or US-20010006233-\$ or US-20020118035-\$ or US-20030111733-\$ or US-20030136993-\$).did.) and (memory dram) ("6599778").PN. ("6545490").PN.	USPAT; US-PGPUB	2003/08/04 18:23
-	1		USPAT	2003/08/04 18:56
-	1		USPAT	2003/08/04 18:56
-	33	(US-6300647-\$ or US-5734176-\$ or US-6452208-\$ or US-6380555-\$ or US-6452209-\$ or US-6339228-\$ or US-6310361-\$ or US-4905065-\$ or US-6153891-\$ or US-6309897-\$ or US-6277659-\$ or US-6392307-\$ or US-5523586-\$ or US-6498396-\$ or US-6301121-\$ or US-6545490-\$ or US-6377067-\$ or US-6599778-\$ or US-5408131-\$ or US-6078057-\$ or US-5990562-\$ or US-5309446-\$ or US-4914739-\$ or US-4791463-\$ or US-5665978-\$ or US-6576922-\$).did. or (US-6072323-\$ or US-6576923-\$).did. or (US-20010006233-\$ or US-20020063250-\$ or US-20020118035-\$ or US-20030136993-\$ or US-20030111733-\$).did. 051544.AP.	USPAT; US-PGPUB	2003/12/19 18:31
-	7		USPAT; US-PGPUB	2003/12/23 11:39
-	4	((((257/68) or (257/71) or (257/301) or (257/302) or (257/303) or (257/304) or (257/305) or (257/296) or (257/905) or (257/906) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769) or (438/18) or (438/243) or (438/700) or (714/5) or (714/42) or (714/718) or (714/719) or (714/720) or (714/721) or (714/722) or (714/723) or (714/763) or (714/773)).CCLS.) or 257/48.ccls.) and (memory adj2 device memory adj2 element dram).ti,ab,clm. and (vertical trench) and (back adj side backside back-side) and (test testing measure measuring)	USPAT; US-PGPUB	2003/12/23 10:19
-	1094	((((257/68) or (257/71) or (257/301) or (257/302) or (257/303) or (257/304) or (257/305) or (257/296) or (257/905) or (257/906) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769) or (438/18) or (438/243) or (438/700) or (714/5) or (714/42) or (714/718) or (714/719) or (714/720) or (714/721) or (714/722) or (714/723) or (714/763) or (714/773)).CCLS.) or 257/48.ccls.) and (memory adj2 device memory adj2 element dram).ti,ab,clm. and (vertical trench) and (test testing measure measuring contact contacting)	USPAT; US-PGPUB	2003/12/23 10:18

-	538	(((257/68) or (257/71) or (257/301) or (257/302) or (257/303) or (257/304) or (257/305) or (257/296) or (257/905) or (257/906) or (324/537) or (324/765) or (324/766) or (324/767) or (324/768) or (324/769) or (438/18) or (438/243) or (438/700) or (714/5) or (714/42) or (714/718) or (714/719) or (714/720) or (714/721) or (714/722) or (714/723) or (714/763) or (714/773)).CCLS.) or 257/48.ccls.) and (memory adj2 device memory adj2 element dram).ti,ab,clm. and vertical and (groove trench) and (test testing measure measuring contact contacting)	USPAT; US-PGPUB	2003/12/23 10:24
-	697	(257/48).CCLS.	USPAT; US-PGPUB	2003/12/23 11:22